

1) IP1X Test Probe



Specification:

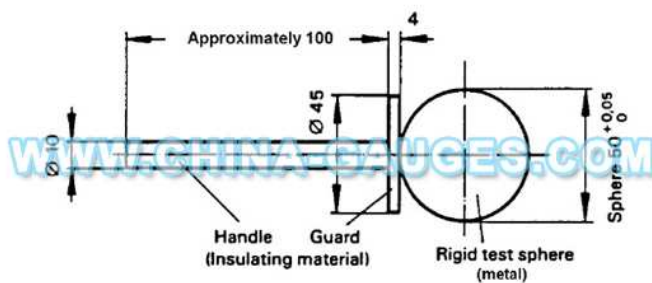
IP1X Probe A /Test Probe A

- 1, According to: IEC 61032:1997 / IEC 60529:2001.
- 2, Test Probe A is necessary appliance for household and similar electrical appliance of against electric shock protection test.

Technical Parameters:

1. Ball Diameter:50 mm
2. Baffle Plate Diameter:45 mm
3. Baffle Plate Thickness: 4 mm
4. Handle Diameter:10 mm
5. Handle Length: 100 mm
6. According to IEC 61032 figure 1 (the Test probe A), table 6 IEC 60529 the first characteristics (1)

a)



Dimensions in millimetres

This probe is intended to verify the protection of persons against access to hazardous parts. It is also used to verify the protection against access with the back of the hand.

Figure 1 – Test probe A

2) IP2X Test Probe



The Jointed Test Finger is a precision test probe made according to Figure 2 (Fig. 2) of the IEC 61032 (Test probe B) and is used to simulate a human finger. It is also used by the standards of CSA, IRAM, UL and in most of the rules involved in the verification of accessibility to live parts.

Technical Parameters:

1. Knurled Finger Diameter:12 mm
2. Knurled Finger Length:80 mm
3. Baffle Plate Diameter:50 mm
4. Baffle Plate Length:100 mm
5. Baffle thickness:20 mm

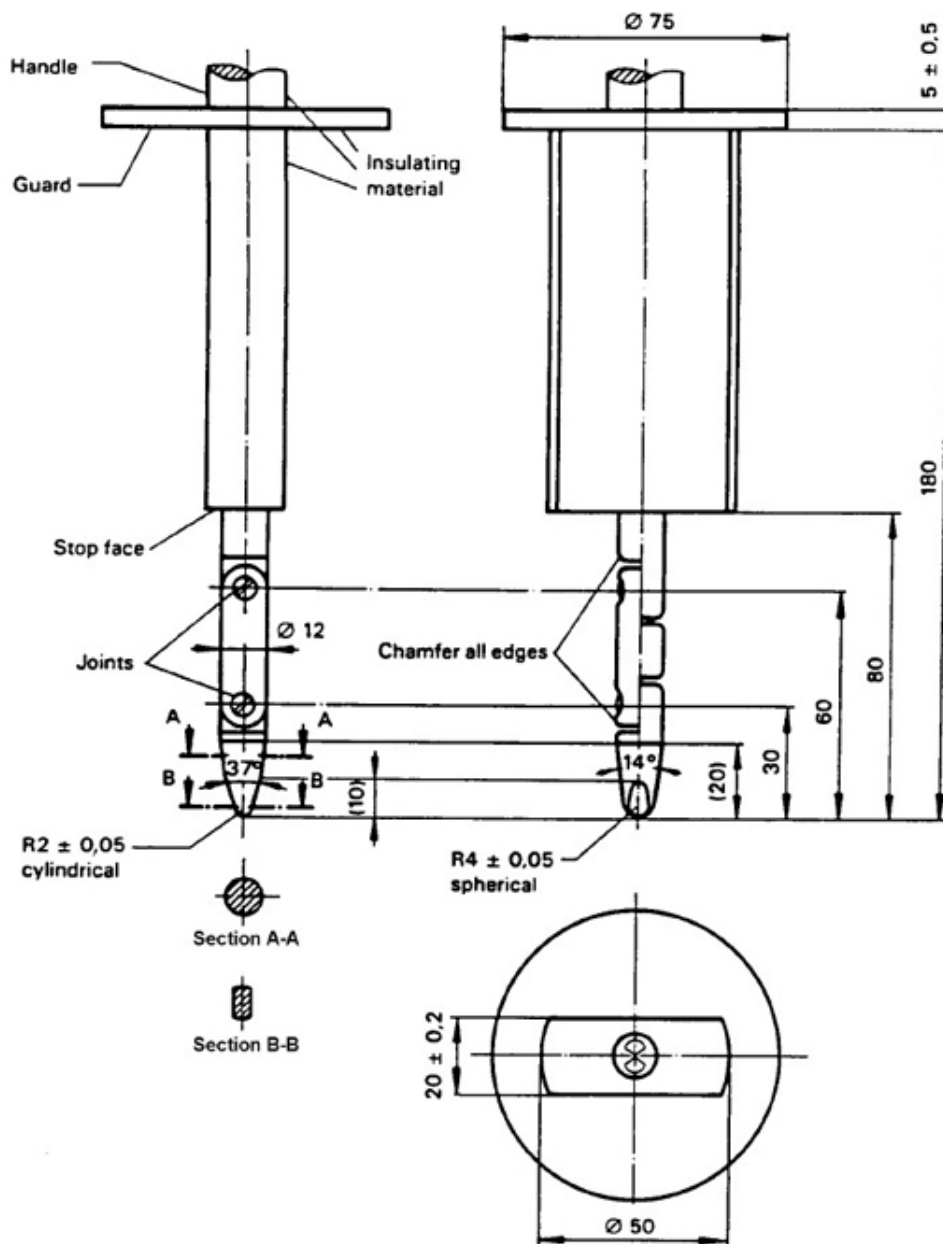
Application:

1. The joint part of The Standard Test Knurled Finger Probe can't touch the live parts or close to the dangerous parts, and 50 mm to 20 mm baffle plate cannot enter.
2. In the prevent electric shock test, wirings, power devices, and lighting devices are needed.

Notes:

Both joints shall permit movement in the same plane and the same direction through an angle of 90° with a 0° to +10° tolerance.

b)



Dimensions in millimetres

Material: metal, except where otherwise specified.

Tolerance on dimensions when no specific tolerance is given:

– on angles: $\begin{matrix} 0 \\ -10^\circ \end{matrix}$

– on linear dimensions: up to 25 mm: $\begin{matrix} 0 \\ -0,05 \end{matrix}$ mm; over 25 mm: $\pm 0,2$ mm.

Both joints shall permit movement in the same plane and the same direction through an angle of 90° with a 0° to $+10^\circ$ tolerance.

This probe is intended to verify the basic protection against access to hazardous parts. It is also used to verify the protection against access with a finger.

Figure 2 – Test probe B

3) IP2XC Test Probe



Basic Introduction:

- 1, According to the DIN40050 IEC60529.
- 2, 12.5MM test probe is necessary appliance for household and similar electrical appliance of against electric shock protection test.

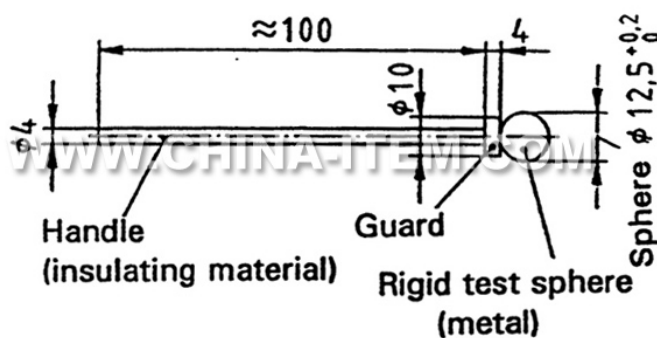
Technical parameters:

- 1, Ball Diameter: 12.5 mm
- 2, Baffle Plate Diameter: 4 mm
- 3, Baffle Plate Thickness: 10 mm
- 4, Handle Diameter: 4mm

Application:

- 1, The ball cannot touch the live parts or approach to hazardous parts.
- 2, In the test requirements of preventing from accessing to the hazardous parts, the test steel ball without thrust needs to be used with pushing tension meter, and steel body needs to exert a 30±3N force on the protection layer.

Sphere Ø 12.5



4) IP3X Test Probe

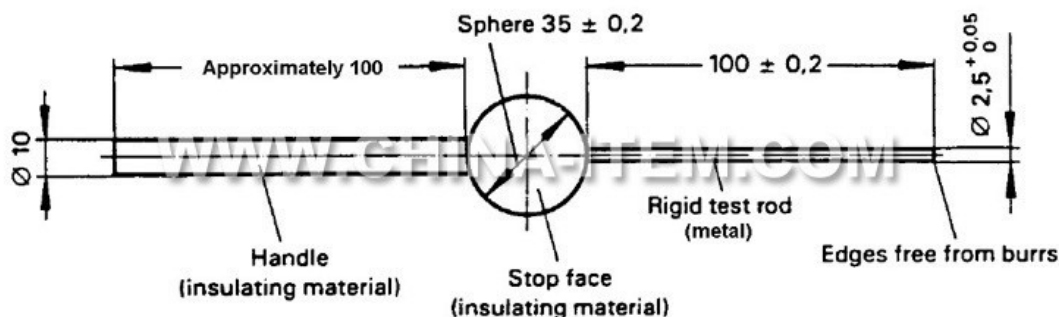


Basic Introduction:

1. According to: IEC 61032:1997 / IEC 60529:2001 / IEC 60065 / IEC 60598 and UL
2. IP3X Test Probe C (Test Probe C) is the necessary tool to proceed protecting electric shock test of household and similar electrical appliances.

Technical parameters:

1. Rod length: 100 mm
2. Rod diameter: 2.5 mm
3. Circular-baffle diameter: 35 mm
4. Handle diameter: 10 mm
5. Handle length: 100 mm
6. According to IEC 61032 figure 3 (the Test probe C). Table 6 GB/T4208-2008 (the first characteristic digital 3)



5) IP4X Test Probe



Basic Introduction:

1. According to: GB/T4208-2008 / IEC 61032:1997 / IEC 60529:2001 / IEC 60065 / IEC 60598 and UL
2. IP4X Test Probe D (Test Probe D) is the necessary tool to proceed protecting electric shock test of household and similar electrical appliances.

Technical parameters:

1. Wire length: 100 mm
2. Wire diameter: 1.0 mm
3. Circular-baffle diameter: 35 mm
4. Handle diameter: 10 mm
5. Handle length: 100 mm
6. According to IEC 61032 figure 4 (the Test probe D).

